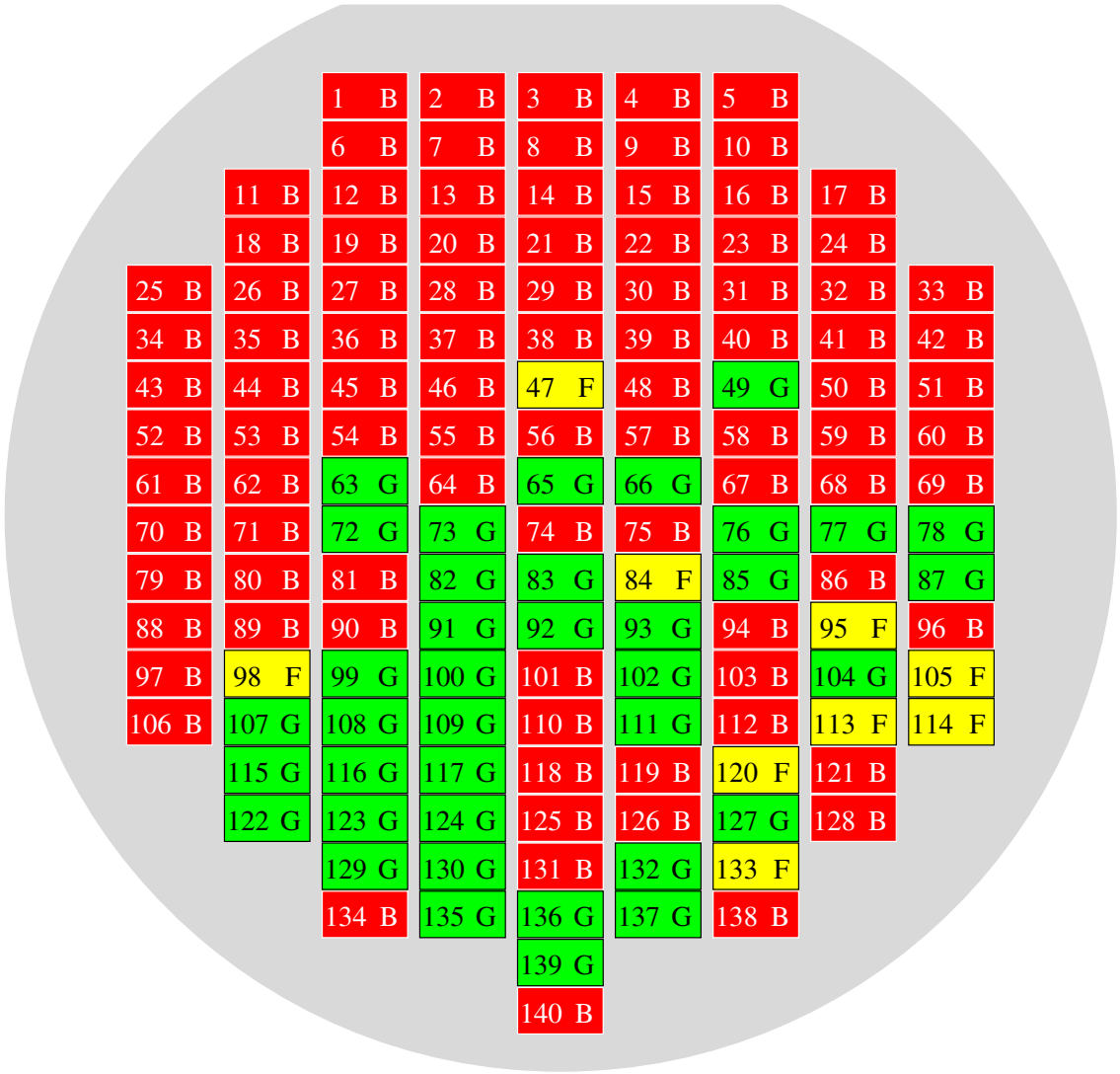
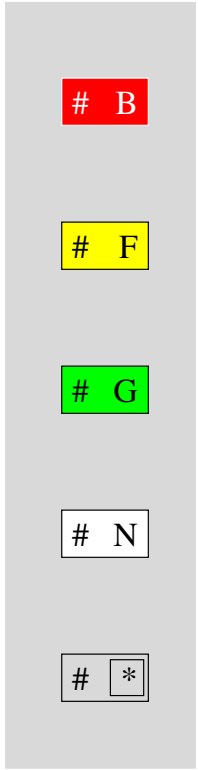
Die quality map for wafer 248 s/n: Y21316-08-02

Date: 12/22/99





Bad die

Fair die

Good die

No info

Manually tagged